
**Evaluation of thickness, density
and interface width of thin films by
X-ray reflectometry — Instrumental
requirements, alignment and
positioning, data collection, data
analysis and reporting**

*Évaluation de l'épaisseur, de la densité et de la largeur de l'interface
des films fins par réflectrométrie de rayons X — Exigences
instrumentales, alignement et positionnement, rassemblement des
données, analyse des données et rapport*





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